


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,739	CHANG ET AL.	
	Examiner	Art Unit	
	VAN T. PHAM	2627	

SEARCHED			
Class	Subclass	Date	Examiner
369		1/21/2006	VP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East (PGPUB; USPAT; USOCR;EPO;JPO;DERWENT;IBM_T DB) 369 (text search only see search history printout).	1/21/2007	VP